

Typical TEM experimental description:

The high-resolution transmission electron microscopy (HRTEM) and selected-area electron diffraction (SAED) were characterized on a JEOL 2010F field emission gun microscope operated at 200 kV. STEM-EDS elemental mapping analysis was performed on a probe aberration-corrected FEI Titan G2 system with ChemiSTEM Technology operated at 200 kV. A probe current of 100 pA was used for STEM imaging and EDS mapping.

See more examples on papers:

[Applied Physics Letters 102 \(8\), 081601 \(2013\).](#)

[Microscopy and Microanalysis 21 \(04\), 946-952 \(2015\).](#)